

Infringement Analysis Process

Phase I

Potential for Infringement Search
3-4 hrs/patent
Detailed Claim Analysis

No Potential

Potential found

No Potential Infringement
Terminate Search

Potential Infringement
Ease of detection Analysis

Difficult

Easy

Easy

Standards
Standard Essential
6hrs/patent for EoU Chart

Public Literature
Product Infringement
6hrs/patent for EoU Chart

System Testing

Circuit level Testing

Black Box Testing

Reverse Engineering
Customized for specific analysis

Visual Inspection

Board Level Testing

Chip Level Testing

